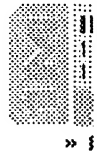


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- 4) Limit the results by selecting Search Options.
- 5) Click Search. See [Search Examples](#)

edge In: Full-text & All Fields

And

rough In: Full-text & All Fields

And

Ikeda In: Author

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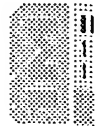
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edge In: Full-text & All Fields

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rough In: Full-text & All Fields

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yamaguchi In: Author

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 edge In: **Full-text & All Fields**

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 rough In: **Full-text & All Fields**

And

 terasawa In: **Author**

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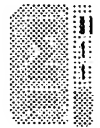
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edge In: [Full-text & All Fields](#)

And

rough In: [Full-text & All Fields](#)

And

lizumi In: [Author](#)

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Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.

Example: optical <and> (fiber <or> fibre) <in> ti

- 3) Limit the results by selecting Search Options.

- 4) Click Search. See [Search Examples](#)

(line <and> edge <and> roughness) <in> ti

Start Search

Clear

Note: This function returns plural and suffixed forms of the keyword(s).

Search operators: <and> <or> <not> <in> [More](#)

Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)

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 (line <and> edge <and>
 roughness <and> measure)

Start Search

Clear

Note: This function returns plural and suffixed forms of the keyword(s).

 Search operators: <and> <or> <not> <in> [More](#)

 Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)
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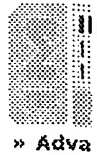
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 (surface <and> roughness
<and> measure) <in> ti

Start Search

Clear

Note: This function returns plural and suffixed forms of the keyword(s).

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 (surface <and> roughness
 <and> measure <and> least
 <and> square)

Note: This function returns plural and suffixed forms of the keyword(s).

 Search operators: <and> <or> <not> <in> [More](#)

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(surface <and> roughness
<and> (line <or> edge) <and>
(estimation <or>
approximation))

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